

Assessing crystallographic data quality

Let's talk about errors, and mistakes

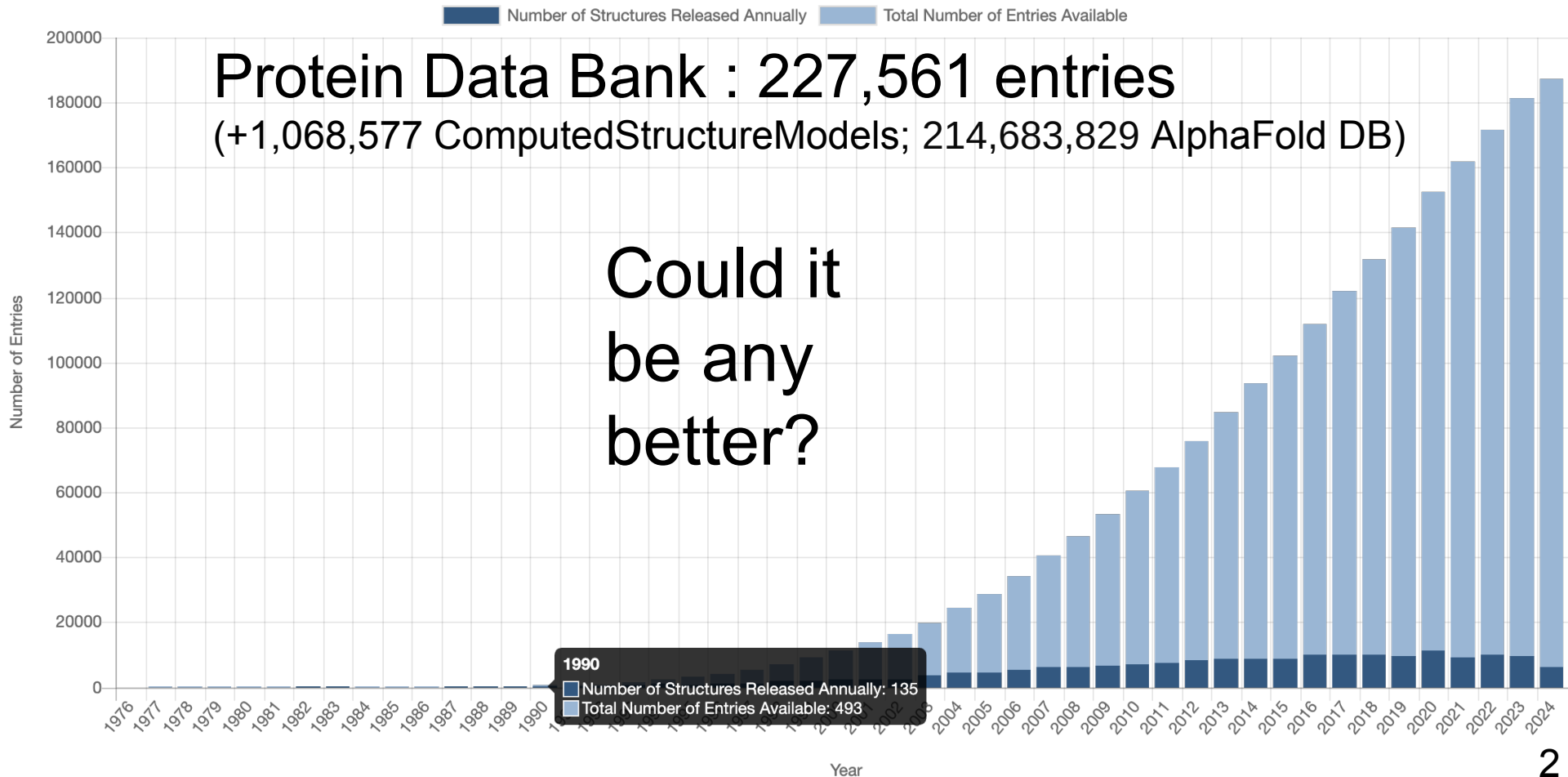
Kay Diederichs

`kay.diederichs@uni-konstanz.de`



CCP4@DLS 2024-11-26

Crystallography has been extremely successful



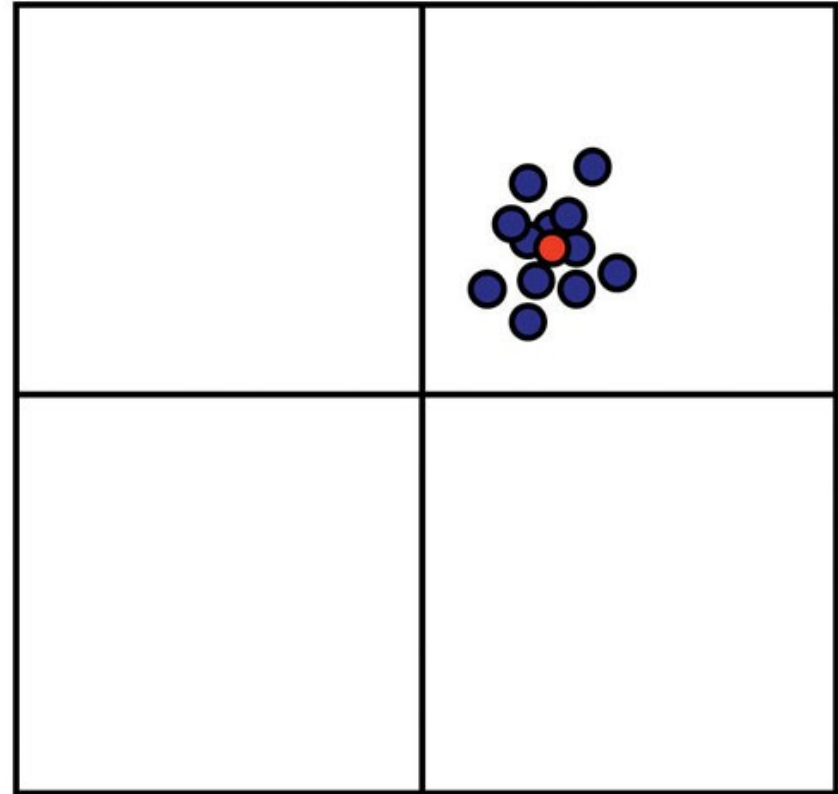
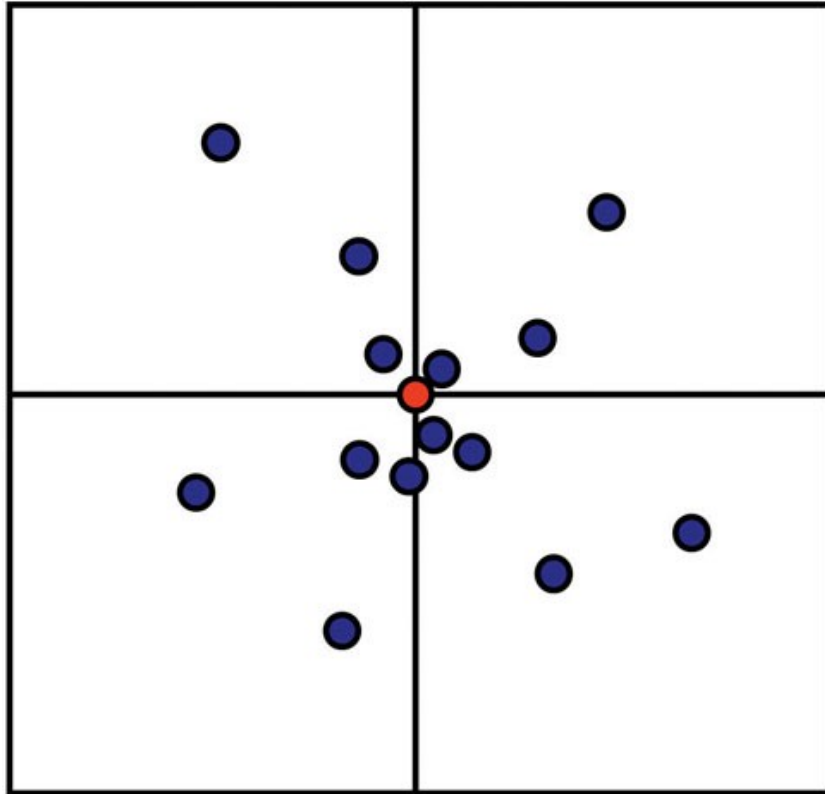
However ...

- *Crystallography is difficult to understand. Why?*
- Macromolecular crystallography suffers from *rules* that may have been useful in the past, but are still commonly used today and result in *wrong decisions*, and *misunderstandings*
- Another reason for the misunderstandings (and difficulties for those learning and practising crystallography) is that we keep *comparing the wrong indicators*
- Data quality statistics are presented in *confusing* and wrong ways

1st example: let's talk about the difference between, and the relevance of **precision** and **accuracy**



“Quality”



© Garland Science 2010

B. Rupp, Bio-
molecular
Crystallography

Accuracy
Precision

– how different from the *true value*?
– how different are *measurements*
from each other?

Numerical example

Repeatedly determine $\pi=3.14...$ as 3.1, 3.2, 3.0 :

observations have **medium precision, medium accuracy**

Precision= relative |deviation from average value|=

$$(0+0.1+0.1)/(3.1+3.2+3.0) = 2.2\%$$

Accuracy= relative |deviation from true value|:

$$=(|3.14-3.1| + |3.14-3.2| + |3.14-3.0|)/(3*3.14) = 2.5\%$$

Repeatedly determine $\pi=3.14...$ as 2.70, 2.71, 2.72 :

observations have **high precision, low accuracy.**

Precision=

$$(0.01+0+0.01)/(2.70+2.71+2.72) = 0.24\%$$

Accuracy=

$$(3.14-2.70 + 3.14-2.71 + 3.14-2.72)/(3*3.14) = 13.7\%$$

R_{merge}
formula!

$$R_{\text{merge}} = \frac{\sum_{hkl} \sum_{i=1}^n |I_i(hkl) - \bar{I}(hkl)|}{\sum_{hkl} \sum_{i=1}^n I_i(hkl)}$$

pink = data-internal

Calculation of precision needs multiple observations of the same quantity; calculation of accuracy needs the true value.

Deviations from true/targeted value

- **Known systematic effects** can usually be made part of the model, or compensated in data processing.
- If **unknown systematic error** exists, the true value cannot be found from the data. **Averaging of multiple observations** may or may not help.
- If only **random error** exists, **averaging of multiple observations** leads to approximation of the true value. Higher multiplicity → better approximation. In that case, $\langle \text{accuracy} \rangle \sim \langle \text{precision} \rangle$. This is **not true for systematic error**.
- Accuracy and precision differ by the unknown systematic error. **Precision** is an **optimistic estimate** of the **accuracy**!
- Precision can easily be calculated, but not accuracy – because the true value is usually not known.
- *The typical “Table 1” shows data quality indicators estimating precision (only), but what we really want to know is accuracy!*
- *Data accuracy is always worse than what the precision suggests, due to systematic errors that we don’t know about.*

Traditional precision indicators focus on the random error

Random error is due to

- .. the quantum nature of energy: photon counting, and electronic noise in detector, and
- .. **is proportional to square root of measured value.**

In crystallography, random error dominates the error at high resolution.

Systematic error is due to

- .. **Crystal**: variation in crystallization conditions, composition, conformation, *radiation damage during experiment.*
- .. **Beamline**: shadows, absorption, vibrations, varying photon/electron flux.
- .. **Processing software**: inaccurate or incomplete modelling of experiment
- .. **is proportional to measured value** (often 1..10% but sometimes much more e.g. in case of shadows and overloads).

In crystallography, systematic error dominates at low resolution.

There is a single indicator for systematic error in data

- Compare – for a given dataset – the errors of the weak data with those of the strong data. This establishes the so-called “error model”.
- The error model can be analyzed to estimate the I/σ of a (hypothetical) super-strong reflection of this dataset. This is called I -over- σ -asymptotic (**ISa**).
- **ISa depends on the systematic error only** (*not* on crystal size, flux, exposure ...)

Rules of thumb:

<5 something (e.g. spacegroup or indexing) is wrong (unless Electron Diffraction)

5 ..10 marginal data, high systematic error

10 .. 20 more and more useful data

20 .. 30 good data

>30 great data, little systematic error

XDS, XSCALE, AIMLESS and DIALS.SCALE report ISa.

Its reciprocal is the fraction of systematic error in the data.

Example: ISa = 20 corresponds to 5% of systematic error.

2nd example: confusion by
multitude and properties of
crystallographic precision
indicators

Comparing model and data

During and after refinement, we measure the agreement of model and data:

- ... with R-values (R_{work} , R_{free})

$$R = \frac{\sum_{hkl} |F_{\text{obs}}(hkl) - F_{\text{calc}}(hkl)|}{\sum_{hkl} F_{\text{obs}}(hkl)}$$

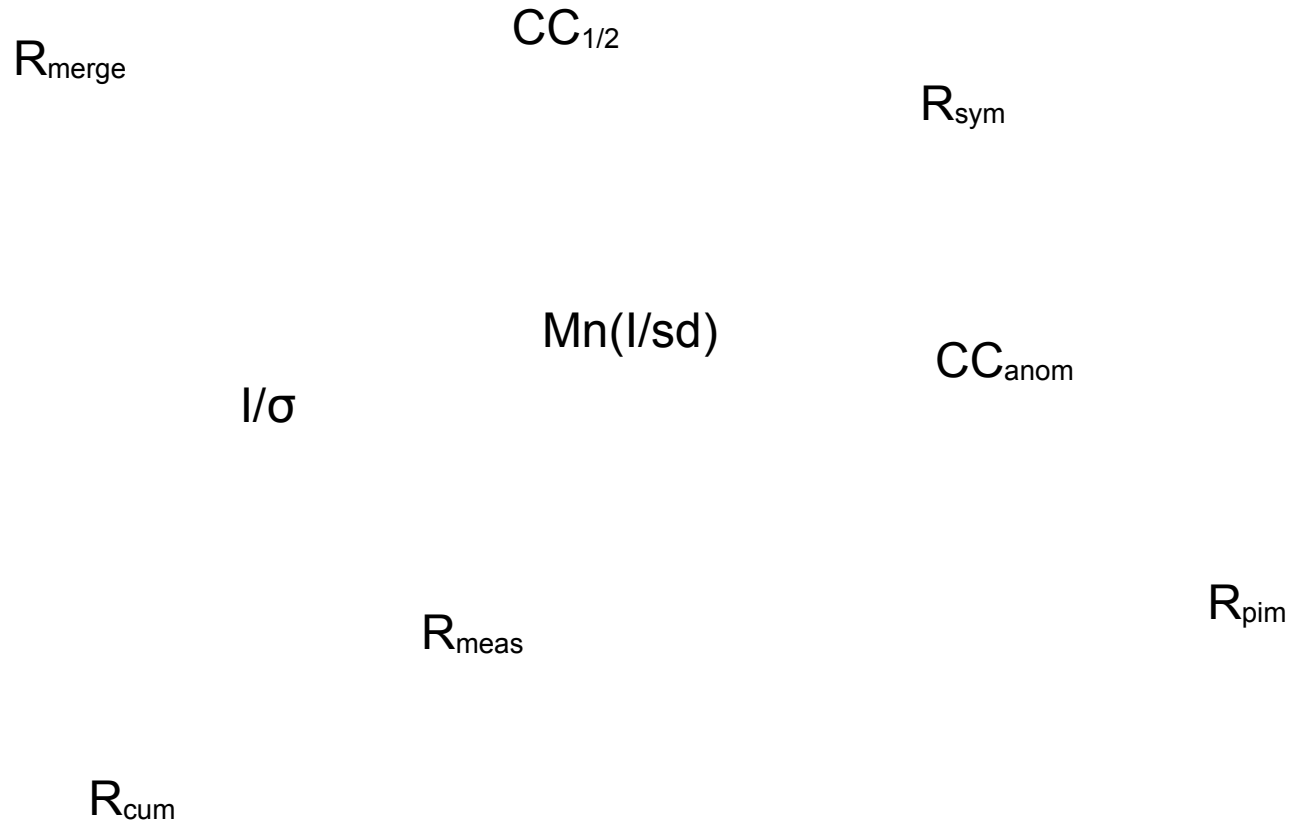
blue=model-vs-data

- ... or with correlation coefficients (CC_{work} , CC_{free})

$$CC = \frac{\sum_{hkl} (I_{\text{obs}}(hkl) - \overline{I_{\text{obs}}})(I_{\text{calc}}(hkl) - \overline{I_{\text{calc}}})}{\sqrt{\sum_{hkl} (I_{\text{obs}}(hkl) - \overline{I_{\text{obs}}})^2 \sum_{hkl} (I_{\text{calc}}(hkl) - \overline{I_{\text{calc}}})^2}}$$

where the sums go over all unique hkl values

For data: confusion – what do these
“Table 1” indicators tell me?



Calculating the precision of unmerged (individual) observations

$$R_{merge} = \frac{\sum_{hkl} \sum_{i=1}^n |I_i(hkl) - \bar{I}(hkl)|}{\sum_{hkl} \sum_{i=1}^n I_i(hkl)}$$

is biased (Diederichs & Karplus, 1997) → shouldn't be used!

$$R_{meas} = \frac{\sum_{hkl} \sqrt{\frac{n}{n-1}} \sum_{i=1}^n |I_i(hkl) - \bar{I}(hkl)|}{\sum_{hkl} \sum_{i=1}^n I_i(hkl)}$$

$\langle |I_i/\sigma_i| \rangle$ (σ_i from error propagation)

→ $R_{meas} \approx 0.8 / \langle |I_i/\sigma_i| \rangle$ if error estimates internally consistent

averaging/"merging": $I = \frac{\sum_1^N \frac{I_i}{\sigma_i^2}}{\sum_1^N \frac{1}{\sigma_i^2}}$

and

$$\sigma = \sqrt{\frac{1}{\sum_1^N \frac{1}{\sigma_i^2}}}$$

(Wikipedia "weighted arithmetic mean")

Calculating the precision of merged data

a) using the \sqrt{n} law of error propagation :

$$\langle I/\sigma(I) \rangle$$

$$R_{pim} = \frac{\sum_{hkl} \sqrt{\frac{1}{n-1}} \sum_{i=1}^n |I_i(hkl) - \bar{I}(hkl)|}{\sum_{hkl} \sum_{i=1}^n I_i(hkl)}$$

$$R_{pim} \sim 0.8 / \langle I/\sigma \rangle$$

b) by comparing averages of randomly selected half-datasets X,Y:

H,K,L	I_i of individual measurements	Assignment to half-dataset	Average I of X Y	
1,2,3	100 110 120 90 80 100	X, X, Y, X, Y, Y	100	100
1,2,4	50 60 45 60	Y X Y X	60	47.5
1,2,5	1000 1050 1100 1200	X Y Y X	1100	1075

...

Then calculate **Pearson correlation coefficient: $CC_{1/2}$ on X, Y**

It can be shown that $CC_{1/2} \approx \frac{1}{1 + \frac{2}{\langle I/\sigma \rangle^2}}$

e.g. $\langle I/\sigma \rangle = 1 \rightarrow CC_{1/2} \approx 33\%$

$\langle I/\sigma \rangle = 2 \rightarrow CC_{1/2} \approx 67\%$

Measuring the precision of merged data with a correlation coefficient

Correlation coefficient $cc_{xy} = \frac{\sum (x_i - \bar{x})(y_i - \bar{y})}{\sqrt{\sum (x_i - \bar{x})^2 \sum (y_i - \bar{y})^2}}$ has clear meaning and well-known statistical properties

a) Significance of its value can be assessed by Student's t-test: could this CC arise by chance (random data)? Typically, call “**significant**” if low likelihood (1% or 0.1%).

b) From $CC_{1/2}$, we can analytically estimate

CC^* = correlation(merged dataset , true intensities)

$$CC^* = \sqrt{\frac{2 CC_{1/2}}{1 + CC_{1/2}}}$$

assuming absence of systematic error.

c) $CC_{\text{work/free}}$ and CC^* are intensity-based → meaningful comparison!

d) If $CC_{\text{work/free}} > CC^*$ then this implies overfitting (because model agrees better with data than the true signal does). This means that $CC_{\text{work/free}}$ in refinement is limited by CC^* : **data quality limits model quality**

Compare model R-values w/ data R-values??

Historical rule: “the quality of the data that I use for refinement can be assessed by R_{merge} . Data with $R_{\text{merge}} > \text{e.g. } 60\%$ are useless.”

Misunderstanding: This is the wrong indicator!

- A model is refined against *merged data*; R_{merge} is for *unmerged data*!
- Model R-values $R_{\text{work/free}}$ are based on *amplitudes*, data R-values $R_{\text{merge}}, R_{\text{pim}}$ on *intensities*
- $R_{\text{merge}}, R_{\text{pim}}$ go to infinity for weak data, whereas $R_{\text{work}}/R_{\text{free}}$ approach a constant ($\sim 60\%$). **Data R-values** thus do not predict model agreement with data → **model and data R-values are not comparable!**

Resulting mistakes: Wrong high-resolution cutoff, wrong data-collection strategy, strong radiation damage, ...

3rd example: *improper* crystallographic reasoning

An example

situation: data to 2.0 Å resolution

refine using all data: $R_{\text{work}}=19\%$, $R_{\text{free}}=24\%$ (overall)

cut at 2.2 Å resolution: $R_{\text{work}}=17\%$, $R_{\text{free}}=23\%$

- **(Wrong) comparison:** “The lower the R-value, the better.” → „cutting at 2.2 Å is better: it gives lower R-values“
→ (Potentially) bad result: throwing away data.
- **Correct question:** which model is better? (the goal of refinement is to optimize the model, not the R-values!)
- **Insight:** indicators may only be compared if they refer to the *same* reflections.

„Paired refinement technique“

*“ideally, we would determine the point at which adding the next shell of data is not adding any statistically significant **information**”* (Phil Evans, 2011)

- calculate F_{calc} from unchanged **higher-res model** but **compare** R-values of only the lower-res reflections against those of the **lower-res model**
- the better model has the lower R_{free} , and the lower $R_{\text{free}}-R_{\text{work}}$ gap
- can be repeated for different high-res cutoffs
- available in PDB-REDO and PAIREF (standalone or CCP4)
- leads to a logical **decision about the high-resolution cutoff**

Karplus, P.A. and Diederichs, K. (2012) Linking crystallographic model and data quality. *Science* **336**, 1030-1033.

Malý, M., Diederichs, K., Dohnálek, J., Kolenko, P. (2020) Paired refinement under the control of PAIREF. *IUCrJ* **7**, 681-692. <https://pairef.fjfi.cvut.cz>

Resolution of the model

Rule:

the resolution of the *model* is the resolution of the data it was refined against

Concepts:

1. the notion “resolution of a model” is misguided – it answers the wrong question!
2. *resolution of a map* (Urzhumtsev *et al*) is well-defined: how far are features apart that we can distinguish? depends on Wilson-B
3. better to ask about precision and accuracy of the model
 - precision: DPI; reproducibility of coordinates
 - accuracy: which errors are present?

Summary

- Crystallographic statistics are plagued by indicators (e.g. R_{merge}) whose properties are misunderstood, but which are perpetuated and enshrined in “*Table 1*”.
- One confusion is the *mix-up of precision and accuracy*.
- Comparing model R-values ($R_{\text{work}}, R_{\text{free}}$) to data R-values ($R_{\text{merge}}, R_{\text{pim}}$) is not sensible. Historically, this attempt has lead to confusing and wrong rules and decisions. Conversely, correlation coefficients as a function of resolution can be meaningfully compared, and interpreted.
- Yet another source of confusion is the attempt to compare model R-values ($R_{\text{work}}, R_{\text{free}}$) referring to *different* sets of reflections. This leads to recurring discussions about resolution cutoffs. The way forward is *paired refinement*.

Thank you for your attention!

References:

- Diederichs, K. (2009) Simulation of X-ray frames from macromolecular crystals using a ray-tracing approach. *Acta Cryst.* **D65**, 535-542
- Diederichs, K. (2010) Quantifying instrument errors in macromolecular X-ray data sets. *Acta Cryst.* **D66**, 733-740.
- Evans, P. (2011) An introduction to data reduction: space-group determination, scaling and intensity statistics. *Acta Cryst.* **D67**, 282-292.
- Murshudov, G.N. (2011) Some properties of crystallographic reliability index - Rfactor: effect of twinning. *Appl. Comput. Math.* **10**, 250-261.
- Karplus, P.A. and Diederichs, K. (2012) Linking crystallographic model and data quality. *Science* **336**, 1030-1033.
- Karplus, P.A. and Diederichs, K. (2015) Assessing and maximizing data quality in macromolecular crystallography. *Current Opinion in Struct.Biol.* **34**, 60-68.
- Diederichs, K. (2015) Crystallographic data and model quality. in: *Nucleic Acids Crystallography (Ed. E. Ennifar), Methods in Molecular Biology* **1320**, 147-173.
- Malý, M., Diederichs, K., Dohnálek, J., Kolenko, P. (2020) Paired refinement under the control of PAIREF. *IUCrJ* **7**, 681-692.